

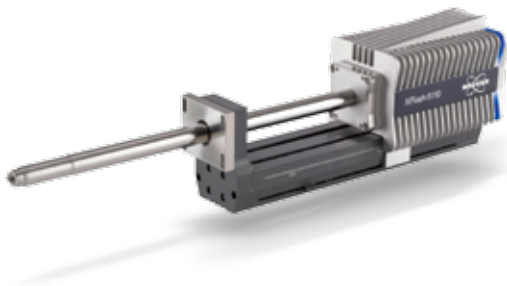


5-on-1 range for SEM

- Advancing compositional and structural analysis with EDS, WDS, EBSD, Micro-XRF and Micro-CT

Unique 5-on-1 range of analytical tools for SEM

Bruker is the world's only manufacturer to offer five analysis methods for materials characterization on electron microscopes. Due to the full integration of EDS, WDS, EBSD and Micro-XRF under the new ESPRIT 2.0 software suite, you can now combine data obtained by these complementary methods.



QUANTAX EDS

Our EDS systems for SEM and TEM provide highest energy resolution, maximum throughput and optimum geometry. QUANTAX EDS features the XFlash® 6 detector series with active areas from 10 to 100 mm².

- Best energy resolution down to 121 eV at Mn K α for efficient light element and low energy analysis

- Slim-line detector technology for even more counts at lower beam currents
- Ultra high throughput with over 600 kcps output count rate at 1,500 kcps input with refined pile-up rejection for fastest measurements
- Fully integrated in ESPRIT 2.0

More info at www.bruker.com/quantax-eds-for-sem



NEW!

QUANTAX WDS

The new QUANTAX WDS system enables ultra-sensitive, high resolution X-ray microanalysis in the low energy range. The compact WD spectrometer XSense features a distortion-free non-magnetic parallel beam optics and incorporates latest detector technologies.

- Energy range: 100 eV to 3.6 keV; energy resolution: 4.6 eV at Si K α
- Six diffracting crystals: 200 Å, 80 Å, 60 Å, 30 Å multilayers, TAP and PET

- Auto-aligning optics with secondary optics ensure optimum measurement conditions and large solid angle
- Reliable acquisition with pressure controlled proportional counter
- Easy setup and rapid start of measurement
- Fully integrated in ESPRIT 2.0

More info at www.bruker.com/quantax-wds

QUANTAX EBSD

Our high-end EBSD system, featuring the *eFlash* detector series, sets new standards in combined EBSD/EDS analysis.

- Pattern streaming with up to 630 patterns/s (4x4 binning) or 930 patterns/s (8x8 binning)
- EBSPs with up to 1600x1200 pixels
- Fastest simultaneous EBSD and EDS acquisition and analysis at speeds of up to 930 points/s

- In-situ vertically adjustable detectors for maximum analytical flexibility
- Unique ARGUS™ FSE/BSE imaging system for microstructure visualization in color
- Transmission Kikuchi Diffraction (TKD) in SEM for materials characterization on the nanoscale
- Fully integrated in ESPRIT 2.0

More info at www.bruker.com/quantax-ebsd



QUANTAX Micro-XRF

XTrace, our new micro-spot X-ray source adds the capabilities of a complete Micro-XRF spectrometer to your SEM – but without the investment.

- Polycapillary optics for spot sizes below 40 µm
- 20 to 50 times better sensitivity for heavier elements compared to e-beam excitation improves trace element detection

- Detection limit: typically 100 ppm down to 10 ppm
- Enhanced analytical accuracy through combination of quantitative results from both electron and X-ray induced spectra
- Fully radiation protected system, radiation < 1 µSv/h
- Fully integrated in ESPRIT 2.0

More info at www.bruker.com/quantax-micro-xrf

NEW!



Micro-CT for SEM

Micro-CT for SEM adds true 3D microscopy to your SEM. It enables the non-destructive measurement and volume visualization of a sample's internal microstructure.

- Non-destructive information on a sample's internal morphology in 2D and 3D
- No sample preparation required

- Resolution down to 400 nm pixel size
- Intuitive and easy-to-use software for 3D rendering and visualization

More info at www.bruker.com/micro-ct-for-sem





ESPRIT 2.0

Our unique 4-in-1 software suite ESPRIT 2.0 allows full control and flexible combination of up to four analytical methods via a single user interface.

- Seamless integration of EDS, WDS, EBSD and Micro-XRF
- Intuitive intra- and inter-method navigation
- Enhanced analytical power through synergistic combination of results delivered by different methods
- Extensive automation tools including new scripting environment for fully customized workflow solutions



For more information on our 5-on-1 range for SEM visit www.bruker.com/quantax



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